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| Substitute Form PTO-1449 (Modified) | U.S. Department of Commerce Patent and Trademark Office | Attorney's Docket No. 12406-147US1 | Application No. 10/567,883 |
| Information Disclosure Statement by Applicant (Use several sheets if necessary) | | Applicant Wilhelm Stein et al. | |
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(37 CFR §1.98(b))

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| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
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| | | | | | | | Yes | No |
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| Examiner Signature /Feifei Yeung Lopez/ (08/14/2008) | Date Considered |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |